

Notice of References Cited	Application/Control No. 10/526,181		Applicant(s)/Patent Under Reexamination BUSCH ET AL.	
	Examiner TAN X. DINH		Art Unit 2627	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2005/0270960 A1	12-2005	Meinders, Erwin Rinaldo	369/272.1
*	B	US-5,608,715 A	03-1997	Yokogawa et al.	369/275.1
*	C	US-2007/0292678 A1	12-2007	Hikmet, Rifat Ata Mustafa	428/328
*	D	US-2006/0187806 A1	08-2006	Balistreri et al.	369/275.1
*	E	US-5,438,561 A	08-1995	Van et al.	369/100
*	F	US-2003/0128600 A1	07-2003	Noehte et al.	365/200
*	G	US-5,434,840 A	07-1995	Ezuka et al.	369/100
*	H	US-5,738,960	04-1998	Abe, Michiharu	430/21
*	I	US-5,246,758 A	09-1993	Matsui et al.	428/64.6
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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